IP4064CX8; IP4364CX8; IP4366CX8

Integrated SIM card passive filter array with ESD protection to IEC 61000-4-2 level 4

Rev. 02 — 11 February 2010 Product data sheet

1. Product profile

1.1 General description

The IP4064CX8, IP4364CX8 and IP4366CX8 are 3-channel RC low-pass filter arrays which are designed to provide filtering of undesired RF signals in the 800 MHz to 3000 MHz frequency band. In addition, the IP4064CX8, IP4364CX8 and IP4366CX8 incorporate diodes to provide protection to downstream components from ElectroStatic Discharge (ESD) voltages as high as ±15 kV contact discharge according the IEC 61000-4-2 model, far exceeding standard level 4.

All three devices are fabricated using monolithic silicon technology and integrate three resistors and seven high-level ESD-protection diodes in a single Wafer-Level Chip-Scale Package (WLCSP). These features make the IP4064CX8, IP4364CX8 and IP4366CX8 ideal for use in applications requiring the utmost in miniaturization such as mobile phone handsets, cordless telephones and personal digital devices.

1.2 Features and benefits

- Pb-free, RoHS compliant and free of halogen and antimony (Dark Green compliant)
- 3-channel SIM card interface integrated RC filter array
- Integrated 100 Ω/100 Ω/47 Ω series channel resistors
- Integrated ESD protection withstanding ±15 kV contact discharge, far exceeding IEC 61000-4-2 level 4
- WLCSP with 0.4 mm pitch (IP4364CX8 and IP4366CX8) and 0.5 mm pitch (IP4064CX8)

1.3 Applications

- SIM interfaces in e.g. cellular and Personal Communication System (PCS) mobile handsets

2. Pinning information

2.1 Pinning

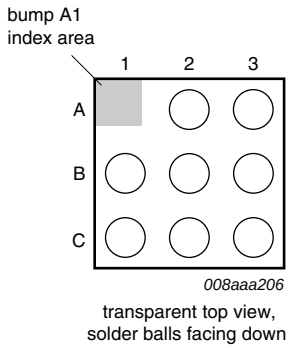


Fig 1. Pin configuration

2.2 Pin description

Table 1. Pinning

Pin	Description
A1	not connected (missing ball)
A2	external pin 1
A3	internal pin 1
B1	external pin 2
B2	ground
B3	internal pin 2
C1	external pin 3
C2	supply ESD protection
C3	internal pin 3

3. Ordering information

Table 2. Ordering information

Type number	Package		
	Name	Description	Version
IP4064CX8/LF/P	WLCSP8	wafer level chip-size package; 8 bumps; 1.41 × 1.41 × 0.65 mm	IP4064CX8/LF/P
IP4364CX8/LF/P	WLCSP8	wafer level chip-size package; 8 bumps; 1.16 × 1.16 × 0.61 mm	IP4364CX8/LF/P
IP4366CX8/P	WLCSP8	wafer level chip-size package; 8 bumps; 1.16 × 1.16 × 0.61 mm	IP4366CX8/P

4. Functional diagram

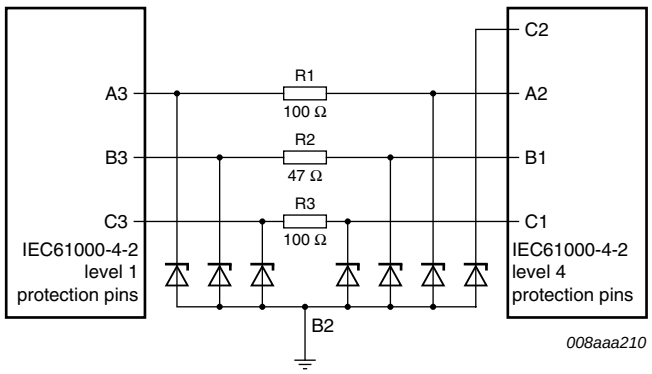


Fig 2. Schematic diagram

5. Limiting values

Table 3. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
V_I	input voltage			−0.5	+5.5	V
V_{ESD}	electrostatic discharge voltage	pins A2, B1, C1 and C2 to ground				
		contact discharge	[1]	−15	+15	kV
		air discharge	[1]	−15	+15	kV
		IEC 61000-4-2 level 4; pins A2, B1, C1 and C2 to ground				
		contact discharge		−8	+8	kV
		air discharge		−15	+15	kV
		IEC 61000-4-2 level 1; pins A3, B3 and C3 to ground				
		contact discharge		−2	+2	kV
		air discharge		−2	+2	kV
P_{ch}	channel power dissipation	continuous power; T_{amb} = 70 °C		-	60	mW
P_{tot}	total power dissipation	continuous power; T_{amb} = 70 °C		-	180	mW
T_{stg}	storage temperature			−55	+150	°C
$T_{reflow(peak)}$	peak reflow temperature	10 s maximum		-	260	°C
T_{amb}	ambient temperature			−35	+85	°C

[1] Device is qualified with 1000 pulses of ±15 kV contact discharges each, according to the IEC61000-4-2 model and far exceeds the specified level 4 (8 kV contact discharge).

6. Characteristics

Table 4. Electrical characteristics

T_{amb} = 25 °C; unless otherwise specified.

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$R_{s(ch)}$	channel series resistance	R1 and R3	75	100	125	Ω
		R2	35.2	47.0	58.8	Ω
C_{ch}	channel capacitance	including diode capacitance; $V_{bias(DC)}$ = 0 V; f = 1 MHz [1]				
		IP4064CX8	14	17	20	pF
		IP4364CX8	14	17	20	pF
		IP4366CX8	8	10	12	pF
V_{BR}	breakdown voltage	I_{test} = 1 mA	6	-	10	V
I_{LR}	reverse leakage current	V_I = 3 V	-	-	50	nA

[1] Guaranteed by design.

7. Application information

7.1 Application diagram

A typical application diagram showing IP4064CX8, IP4364CX8 or IP4366CX8 in a SIM card interface is depicted in Figure 3. The 2 kV ESD compliant pins (A3, B3 and C3) are connected to the baseband interface side while the four 15 kV ESD compliant pins (A2, B1, C1 and C2) are connected to the SIM card.

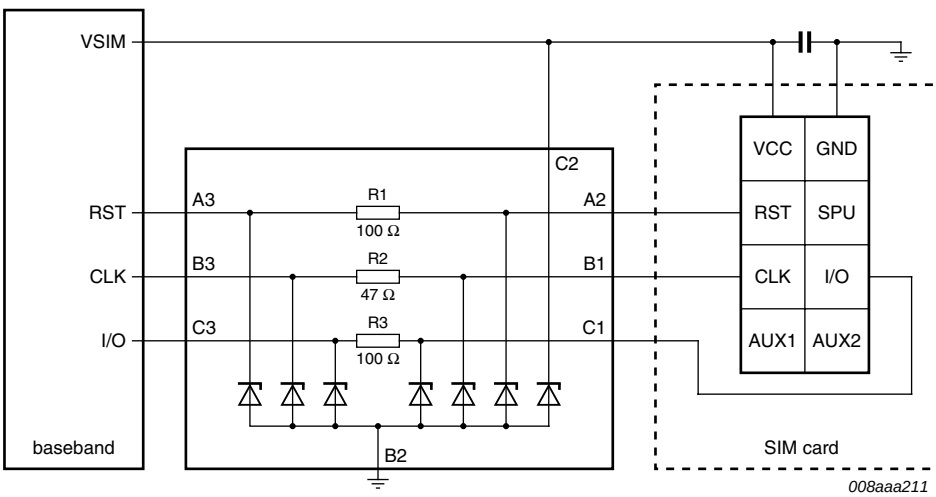


Fig 3. Typical application diagram

7.2 Insertion loss

The IP4064CX8, IP4364CX8 and IP4366CX8 are mainly designed as an EMI/RFI filter for SIM card interfaces. The insertion loss measurement configuration of a typical 50 Ω NetWork Analyzer (NWA) system for evaluation of the IP4064CX8, IP4364CX8 and IP4366CX8 is shown in Figure 4.

The insertion loss in a 50 Ω NWA system for all three channels of IP4064CX8 and IP4364CX8 is depicted in Figure 5a while insertion loss of IP4366CX8 is shown in Figure 5b. The insertion loss is measured with a test Printed-Circuit Board (PCB) utilizing laser drilled micro-via holes that connect the PCB ground plane to the ground pins.

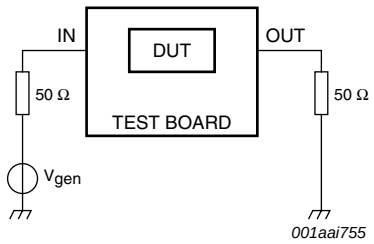
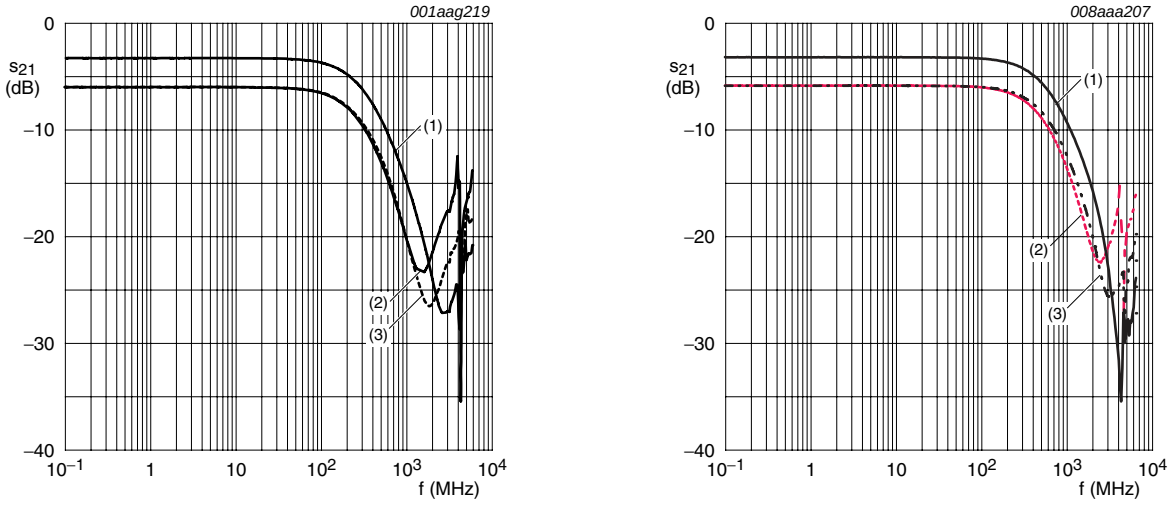


Fig 4. Frequency response measurement configuration



(1) Channel B1 to B3.

(2) Channel A2 to A3.

(3) Channel C1 to C3.

a. IP4064CX8 and IP4364CX8

b. IP4366CX8

Fig 5. Measured insertion loss magnitudes

7.3 Crosstalk

The crosstalk measurement configuration of a typical 50 Ω NWA system for evaluation of the IP4064CX8, IP4364CX8 and IP4366CX8 is shown in Figure 6.

Four typical examples of crosstalk measurement results of IP4064CX8 and IP4364CX8 are depicted in Figure 7a. The crosstalk behavior of IP4366CX8 is shown in Figure 7b. Unused channels are terminated with 50 Ω to ground.

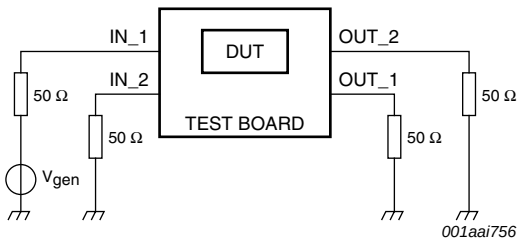
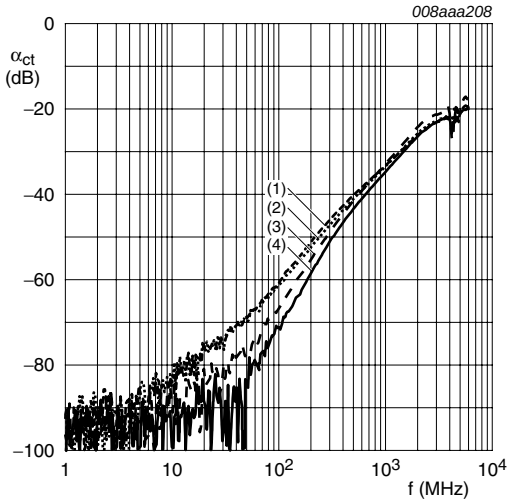
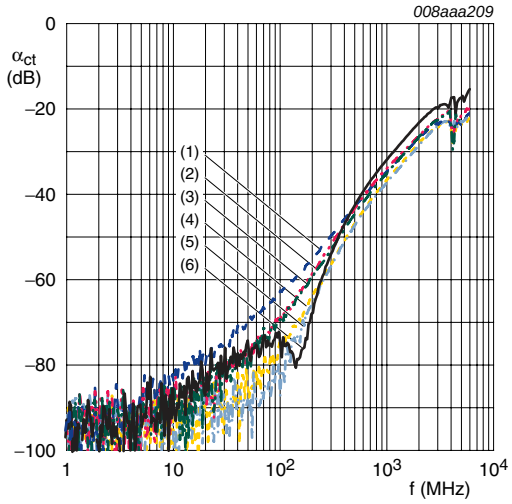


Fig 6. Crosstalk measurement configuration



(1) Pin C1 to pin B3.
(2) Pin B1 to pin C3.
(3) Pin B1 to pin A3.
(4) Pin A2 to pin C3.

a. IP4064CX8 and IP4364CX8



(1) Pin B1 to pin C3.
(2) Pin A2 to pin B3.
(3) Pin B1 to pin A3.
(4) Pin A2 to pin C3.
(5) Pin C2 to pin A3.
(6) Pin C2 to pin C3.

b. IP4366CX8

Fig 7. Measured crosstalk between different channels

8. Package outline

WLCSP8: wafer level chip-size package; 8 bumps (3 x 3 - A1)

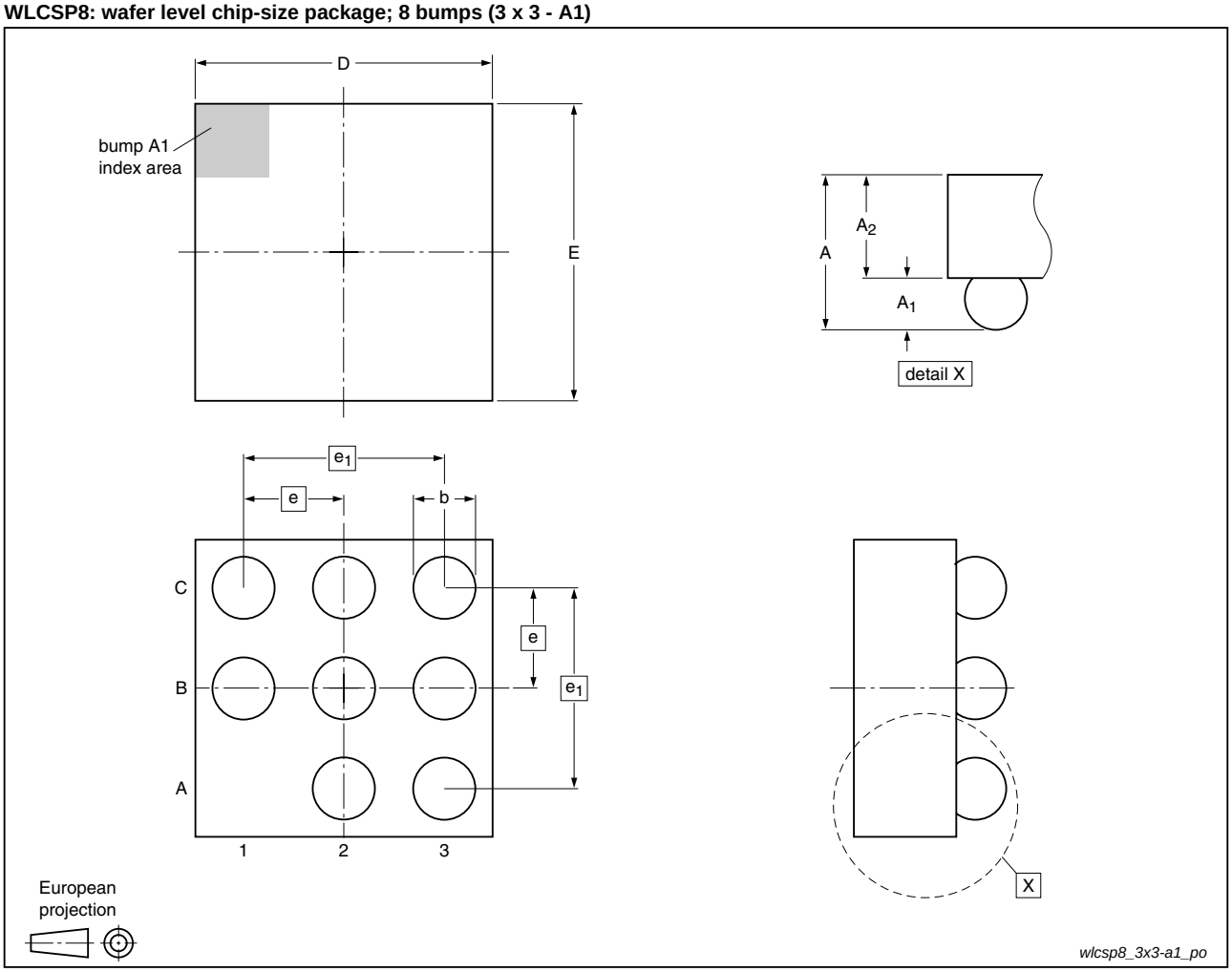


Fig 8. Package outline (WLCSP8)

Table 5. Dimensions for Figure 8

Symbol	Min	Typ	Max	Unit
IP4064CX8				
A	0.60	0.65	0.70	mm
A_1	0.22	0.24	0.26	mm
A_2	0.38	0.41	0.44	mm
b	0.27	0.32	0.37	mm
D	1.36	1.41	1.46	mm
E	1.36	1.41	1.46	mm
e	-	0.5	-	mm
e_1	-	1.0	-	mm
IP4364CX8 and IP4366CX8				
A	0.56	0.61	0.66	mm
A_1	0.18	0.20	0.22	mm
A_2	0.38	0.41	0.44	mm
b	0.21	0.26	0.31	mm
D	1.11	1.16	1.21	mm
E	1.11	1.16	1.21	mm
e	-	0.4	-	mm
e_1	-	0.8	-	mm

9. Soldering of WLCSP packages

9.1 Introduction to soldering WLCSP packages

This text provides a very brief insight into a complex technology. A more in-depth account of soldering WLCSP (Wafer Level Chip-Size Packages) can be found in application note *AN10439 "Wafer Level Chip Scale Package"* and in application note *AN10365 "Surface mount reflow soldering description"*.

Wave soldering is not suitable for this package.

All NXP WLCSP packages are lead-free.

9.2 Board mounting

Board mounting of a WLCSP requires several steps:

1. Solder paste printing on the PCB
2. Component placement with a pick and place machine
3. The reflow soldering itself

9.3 Reflow soldering

Key characteristics in reflow soldering are:

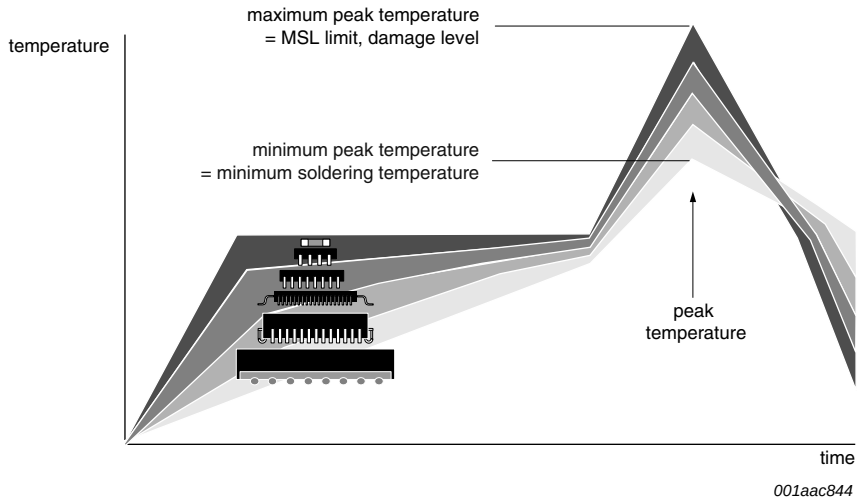
- Lead-free versus SnPb soldering; note that a lead-free reflow process usually leads to higher minimum peak temperatures (see Figure 9) than a PbSn process, thus reducing the process window
- Solder paste printing issues, such as smearing, release, and adjusting the process window for a mix of large and small components on one board
- Reflow temperature profile; this profile includes preheat, reflow (in which the board is heated to the peak temperature), and cooling down. It is imperative that the peak temperature is high enough for the solder to make reliable solder joints (a solder paste characteristic) while being low enough that the packages and/or boards are not damaged. The peak temperature of the package depends on package thickness and volume and is classified in accordance with Table 6.

Table 6. Lead-free process (from J-STD-020C)

Package thickness (mm)	Package reflow temperature (°C)		
	Volume (mm^3)		
	< 350	350 to 2000	> 2000
< 1.6	260	260	260
1.6 to 2.5	260	250	245
> 2.5	250	245	245

Moisture sensitivity precautions, as indicated on the packing, must be respected at all times.

Studies have shown that small packages reach higher temperatures during reflow soldering, see Figure 9.



MSL: Moisture Sensitivity Level

Fig 9. Temperature profiles for large and small components

For further information on temperature profiles, refer to application note *AN10365 "Surface mount reflow soldering description"*.

9.3.1 Stand off

The stand off between the substrate and the chip is determined by:

- The amount of printed solder on the substrate
- The size of the solder land on the substrate
- The bump height on the chip

The higher the stand off, the better the stresses are released due to TEC (Thermal Expansion Coefficient) differences between substrate and chip.

9.3.2 Quality of solder joint

A flip-chip joint is considered to be a good joint when the entire solder land has been wetted by the solder from the bump. The surface of the joint should be smooth and the shape symmetrical. The soldered joints on a chip should be uniform. Voids in the bumps after reflow can occur during the reflow process in bumps with high ratio of bump diameter to bump height, i.e. low bumps with large diameter. No failures have been found to be related to these voids. Solder joint inspection after reflow can be done with X-ray to monitor defects such as bridging, open circuits and voids.

9.3.3 Rework

In general, rework is not recommended. By rework we mean the process of removing the chip from the substrate and replacing it with a new chip. If a chip is removed from the substrate, most solder balls of the chip will be damaged. In that case it is recommended not to re-use the chip again.

Device removal can be done when the substrate is heated until it is certain that all solder joints are molten. The chip can then be carefully removed from the substrate without damaging the tracks and solder lands on the substrate. Removing the device must be done using plastic tweezers, because metal tweezers can damage the silicon. The surface of the substrate should be carefully cleaned and all solder and flux residues and/or underfill removed. When a new chip is placed on the substrate, use the flux process instead of solder on the solder lands. Apply flux on the bumps at the chip side as well as on the solder pads on the substrate. Place and align the new chip while viewing with a microscope. To reflow the solder, use the solder profile shown in application note *AN10365 "Surface mount reflow soldering description"*.

9.3.4 Cleaning

Cleaning can be done after reflow soldering.

10. Abbreviations

Table 7. Abbreviations

Acronym	Description
DUT	Device Under Test
EMI	ElectroMagnetic Interference
ESD	ElectroStatic Discharge
NWA	NetWork Analyzer
PCB	Printed-Circuit Board
PCS	Personal Communication System
RFI	Radio Frequency Interference
RoHS	Restriction of Hazardous Substances
SIM	Subscriber Identity Module
WLCSP	Wafer-Level Chip-Scale Package

11. Revision history

Table 8. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
IP4064CX8_IP4364CX8_ IP4366CX8_2	20100211	Product data sheet	-	IP4064CX8LF_IP4364CX8LF_1
Modifications:	• Type number IP4366CX8 added • Figure 3: added • General editorial update			
IP4064CX8LF_IP4364CX8LF_1	20071112	Product data sheet	-	-

12. Legal information

12.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

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14. Contents

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